


<b>Search Notes</b>  	<b>Application/Control No.</b>  10553501	<b>Applicant(s)/Patent Under Reexamination</b>  LEE, BAEK-WOON
	<b>Examiner</b>  MY-CHAU T TRAN	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
345	55, 84, 87, 88, 90, 92, 93, 103	12/18/2008	MCT
UPDATED	UPDATED - see printout	06/11/2009	MCT
UPDATED	UPDATED - see printout	12/12/2009	MCT

SEARCH NOTES		
Search Notes	Date	Examiner
PALM Inventor; WEST - see printout	12/18/2008	MCT
Reviewed for ODP the following Patent(s) and/or Application(s): 11/224,038	12/18/2008	MCT
UPDATED - see printout	06/11/2009	MCT
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INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
345	87, 88, 90, 92; see printout	12/12/2009	MCT

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